

Using Side Channel Information for Improving Data Partitioning Strategy to Test Smart Cards

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Our Motivation

- ▶ We have a **black box** approach;
- ▶ A smart card application may contain any **hidden feature**;
- ▶ If some commands are hidden, **how to find it?**

Outline

- 1 Introduction
 - Fuzzing to Discovering Vulnerabilities
 - Testing Smart Card Application
 - Side Channel Attacks
- 2 Enhancing the Data Generator with Data Portioning
 - Creating the Partitions
 - Example: an One Time Password
 - Evaluation & Limits of the Approach
- 3 Conclusion & Future Works

Fuzzing to Discovering Vulnerabilities

- ▶ It is a technique used to uncover vulnerabilities
- ▶ 3 modules
 - Data Generator
 - Delivery Mechanism
 - Monitoring System



State-of-the-art Fuzzing Techniques

Mutation-based fuzzer

- ▶ Mutates correct data to invalid one.

Generation-based fuzzer

- ▶ More smart than the mutation-based fuzzer
- ▶ Commands are generated from the specification

Current Fuzzers Limitations

- ▶ Tests case combinatorial explosion!
- ▶ Limiting the test coverage
 - Generate values around the input
- ▶ Partitioning the input domain
 - Specification or implementation is required
 - Does not work on a black box context

The Smart Card



- ▶ Widely used device
 - Credit Card;
 - (U)SIM Card;
 - Health Card (french Vitale card);
 - Pay TV;
 - ...
- ▶ Most of them embed a Java Virtual Machine

The Smart Card



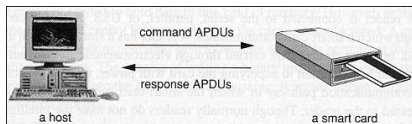
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 - Pay TV;
 - ...
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How to test a Java Card Application?

- ▶ Model-based approach
- ▶ Only dedicated for functional testing ...

Java Card Application

The APDU command



APDU Command

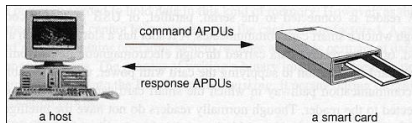
Header				Body		
CLA	INS	Parameter 1	Parameter 2	Lc	Data field	Le

APDU Response

Data field	Status Word
------------	-------------

Java Card Application

The APDU command



APDU Command

Header				Body		
CLA	INS	Parameter 1	Parameter 2	Lc	Data field	Le
P_0	P_1	P_2	P_3			

APDU Response

Data field	Status Word
------------	-------------



Fuzzing a Java Card Application

- ▶ C&SAR 2011: Testing on Java Card Web Server upon several smart card's protocols; (Barreaud *et al.*)
 - Testing an implementation from its specification
- ▶ SSTIC 2011: Fuzzing on EMV protocol; (Lancia)
 - Reference Implementation Vs tested implementation
- ▶ ECIWS 2010: Fuzzing to discover hidden command; (Guyot)
- ▶ Alimi's Master Thesis (2012): Fuzzing based on genetic algorithm

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How to choose the input data?



Side Channel Attacks

“In cryptography, a side channel attack is any attack based on information gained from the physical implementation of a cryptosystem, rather than brute force or theoretical weaknesses in the algorithms (compare cryptanalysis)” (source: Wikipedia)

- ▶ Timing attacks;
- ▶ Power monitoring attacks;
- ▶ Electromagnetic attacks;
- ▶ Acoustic cryptanalysis;
- ▶ Differential fault analysis;
- ▶ Data remanence.



How to generate interesting input data?

- ▶ Combined timing attack and fuzzing
- ▶ Partitioning regarding to the time response

Step 1: Get Evaluation Order

Data: P the set of input parameters

Result: C the set of data partition

$Min \leftarrow \emptyset$; $C \leftarrow \emptyset$; $InitParameter()$;

for $i \leftarrow 0$ **to** $MAXPARAMS$ **do**

$P_i \leftarrow NON_VALID_VALUE$;
 $t_{i,j} \leftarrow Send(P_{i,j}, data)$;

end

$SortedOrder \leftarrow Sort(t_{i,j})$;

- ▶ Testing incorrect values from the specification.
- ▶ Only one incorrect value by parameter is tested

Steps 2 & 3: Hidden Command & Build Partition

```

for  $i \in 0$  to MAXPARAMS using the
SortedOrder do
  |
  for  $j \leftarrow 0$  to MAXBYTE do
    |
     $P_i \leftarrow j$ ;
     $t_{i,j} \leftarrow \text{Send}(P_{i,j}, \text{data})$ ;
  end
  InitParameter();  $\text{Min}_i \leftarrow \text{Sort}(t_i)$ ;
  for  $j \leftarrow 0$  to MAXBYTE do
    |
     $\text{Mean}(t_{i,j})$ ;
    if  $t_{i,j} > \text{Mean}(t_{i,j}) + \delta$  then
      |
       $C_i \leftarrow \text{CreateNewPartition}(j)$ ;
    end
  end
end

```

- ▶ Each element is tested from the evaluation order.
- ▶ The response time depends to a card and reader delay (δ)
- ▶ According to the response time, a partition is created

Step 4: Fuzz it!

```

Sort(Min);
DefineCFG(Min);
// Fuzzing step
for  $i \leftarrow 0$  to MAXPARAMS do
  | for  $j \in$  each subdomain of  $C_i$  do
  | |  $Res_{i,j} \leftarrow$  Send( $P_{i,j}$ , data);
  | end
end

```

- ▶ Resorting the response time to take in count the hidden command
- ▶ Generating the real tested application CFG
- ▶ Fuzzing each application's subdomain

Example: a One Time Password I

- ▶ One Time Password (OTP) generates keyed hash using DES algorithm
- ▶ The specification defines:
 - $P_0 = 0x00$
 - $P_1 \in \{0x34, 0x36, 0x38\}$
 - $P_2 = 0x00$
 - $P_3 \in [0x50, 0x57]$ for the get and put data command
 - $P_3 \in \{0x0, 0x1\}$ for the verify PIN command

Example: a One Time Password II

```
public void process(APDU apdu) throws ISOException {
    if (selectingApplet()) return;
    byte[] cmd_apdu = apdu.getBuffer();
    Util.arrayFillNonAtomic(wy, 0, LEN_WY, 0);
    if (cmd_apdu[ISO7816.OFFSET_CLA]
        == ISO7816.CLA_ISO7816 /*=0x00*/) {
        switch(cmd_apdu[ISO7816.OFFSET_INS]) {
            case INS_VERIFY /*0x34*/: cmdVERIFY(apdu); break;
            case INS_PUTDATA /*0x36*/: cmdPUTDATA(apdu); break;
            case INS_GETDATA /*0x38*/: cmdGETDATA(apdu); break;
            default : ISOException.throwIt
                (ISO7816.SW_INS_NOT_SUPPORTED);
        } } else {
        ISOException.throwIt(ISO7816.SW_CLA_NOT_SUPPORTED);
    } }
```

Fuzzing Applied to the OTP Implementation I

- ▶ We applied the fuzzing approach on the OTP implementation;
- ▶ The evaluation order of each parameter is discovered:
 - ① P_0 (CLA)
 - ② P_1 (INS)
 - ③ P_2 (P1)
 - ④ P_3 (P2)
- ▶ Two evaluations process: without and with the PIN validation.

Fuzzing Applied to the OTP Implementation II

- ▶ We search the hidden command & we build the partition;
- ▶ We test the 255-value of the P_0 (CLA) parameter:
 - **2 partitions** are discovered
 - One for P_0 (CLA) equals 0
 - One for the rest;
- ▶ The same process is done with other parameters:

Fuzzing Applied to the OTP Implementation III

```
private void cmdGETDATA(APDU apdu) {
    byte[] cmd_apdu = apdu.getBuffer();
    // if ((P1 != 0) || (P2 < 0x50) || (P2 > 0x57))
    //     => Exception(SW_WRONG_P1P2)
    short le = (cmd_apdu[ISO7816.OFFSET_LC] & 0x00FF);
    switch(tag) { ...
        case (byte) 0x57: // get a new NSU
            if (le != (byte)8) // Exception(SW_WRONG_LENGTH)
                if (!userpin.isValidated())
                    // Exception(SW_SECURITY_STATUS_NOT_SATISFIED)
                if (stateMachine!=INIT_DONE)
                    // Exception(SW_DATA_INVALID+2)
                    generateNSU(); ...
            default: // => Exception(SW_DATA_NOT_FOUND)
    } apdu.setOutgoingAndSend ((short) 0, (short) le); }
```

Evaluation

- ▶ A learning step is needed to find the δ value (response time).
- ▶ Checking the code coverage of our approach
 - Developing a **code coverage API** for Java Card
- ▶ Our approach works due to the particular way of programming Java Card applet.
- ▶ Our approach is limited to the number of partitions of each parameter: **144 tests** to discover any **hidden command**.
- ▶ Testing each APDU header possibilities requires **264 435 456 tests**.

Limits of the Approach

- ▶ On a **constant time application**, none hidden command will be discovered;
- ▶ Incorrect commands can **kill** the targeted card;
- ▶ Our approach is currently limited to the **APDU header**;
- ▶ Our approach is mainly **limited** to the smart card world . . .

To Conclude

- ▶ A new method for testing software was presented;
 - Based on Side Channel Information to generate data;
 - Discover hidden command;
- ▶ An associated framework was designed to validate our approach;
- ▶ A constant time program cannot be analyzed . . .

To Conclude

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The Next Step

- ▶ Testing the APDU data fields;
- ▶ Use other side channel information leakages:
 - Electromagnetic field;
 - Analyze oscilloscope curves;
- ▶ Reversing Java Card applet using electromagnetic fields to obtain a better CFG.

5

Thank you for your attention!
Do you have any questions?

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